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061063	0317066	OSP-18862

**INFORMATION DISCLOSURE STATEMENT  
 BY APPLICANT**

Date: December 28, 2009

Page **1** of **1**

Applicant: OKUBO et al.

Appn. No.: 10/544,178

Filing Date: April 24, 2006

Examiner: MOORE, W. Group Art Unit: 2826

**U.S. PATENT DOCUMENTS**

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (If appropriate)
AR						
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
					Enclosed	No
OR	2000-329716 A	11-30-2000	Japan	KUSAKA TAKAO	X	
PR						
QR						
RR						
SR						
TR						
UR						
VR						
WR						
XR						

**OTHER** (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

YR	"Kunio Takayanagi et al., "Semiconductor Measurement Evaluation Dictionary", Japan Science Forum Corporation, September 12, 1997, pages 87-90	X
ZR	Notice of Reasons for Rejection for Japanese Application No. 2004-567897 dated November 4, 2009	X
AAR		
BBR		

Examiner

Date Considered:

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.